

Flash Memory 'Bumping' Attacks

Sergei Skorobogatov

<http://www.cl.cam.ac.uk/~sps32> email: sps32@cam.ac.uk

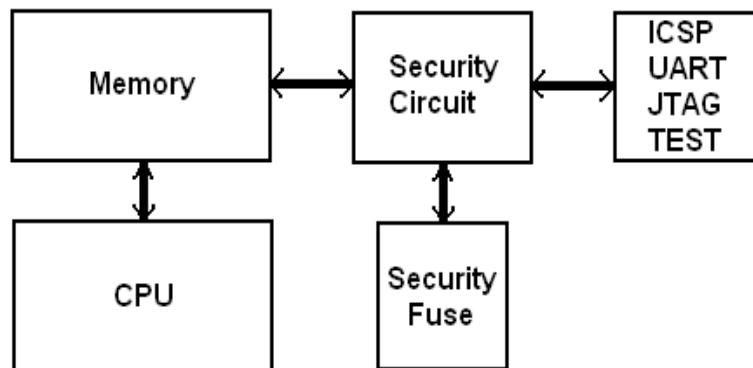


UNIVERSITY OF
CAMBRIDGE

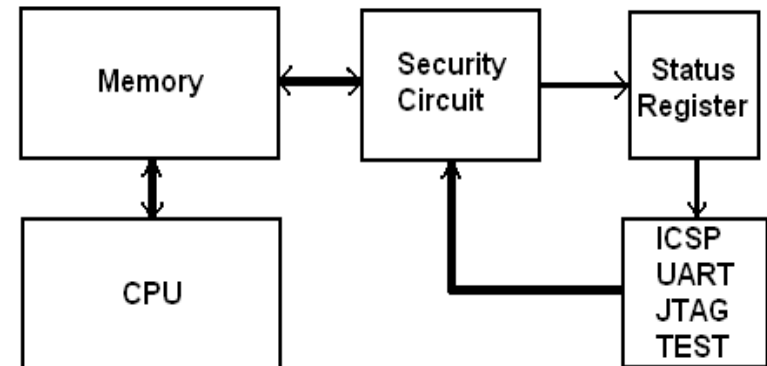
Computer Laboratory

Introduction

- Data protection with integrity check
 - verifying memory integrity without compromising confidentiality
 - How secure is “No Readback” solution?



Readback access controlled by security fuse



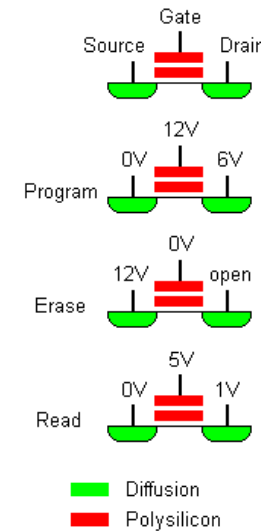
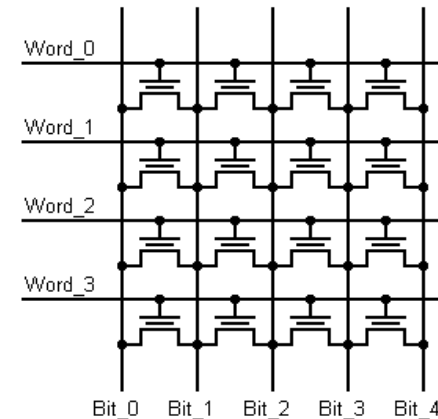
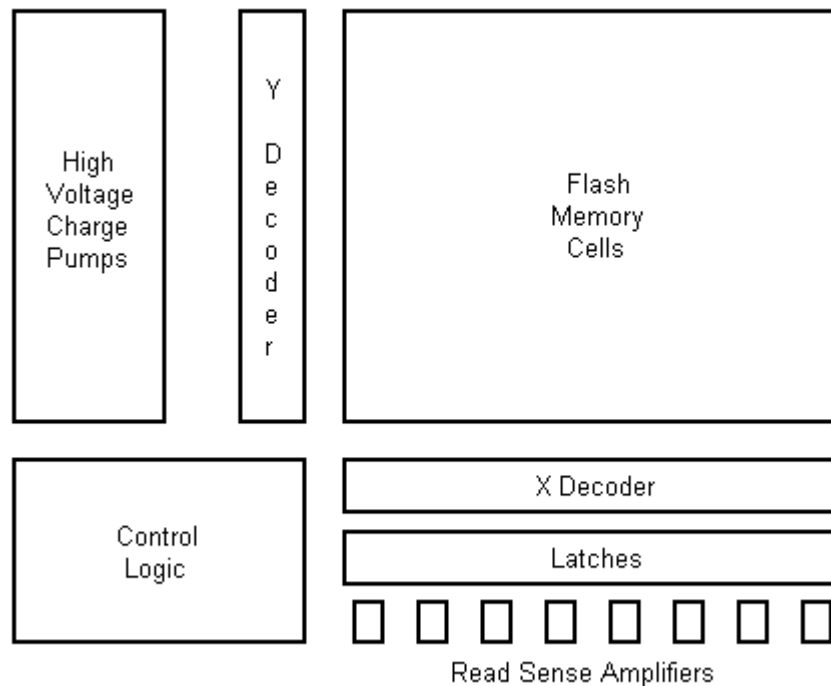
No Readback access
only secure verification

Introduction

- Flash memory prevails
 - usually stores IP, sensitive data, passwords and encryption keys
 - widely used in microcontrollers, smartcards and some FPGAs
 - non-volatile (live at power-up)
 - reprogrammable
- How secure is Flash memory storage?
 - used in smartcards and secure memory chips
 - used in CPLDs by Xilinx and believed to be highly secure
 - used in secure FPGAs by Actel and claimed virtually unbreakable
- Vulnerabilities of Flash memory found during my research
 - power glitching influence on data read from memory (Web2000)
 - optical fault injection changes data values (CHES2002)
 - laser scanning techniques reveal memory contents (PhD2004)
 - data remanence allows recovery of erased data (CHES2005)
 - optical emission analysis allows direct data recovery (FDTC2009)

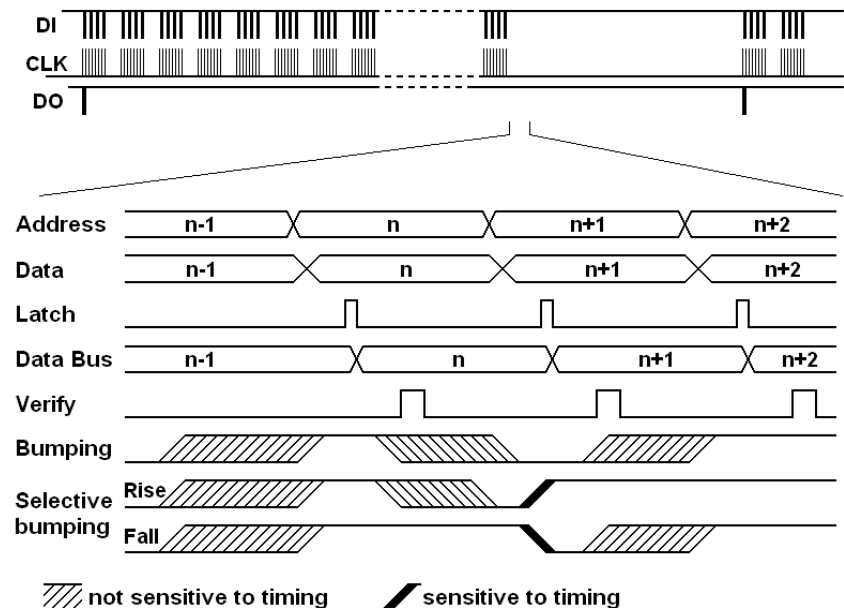
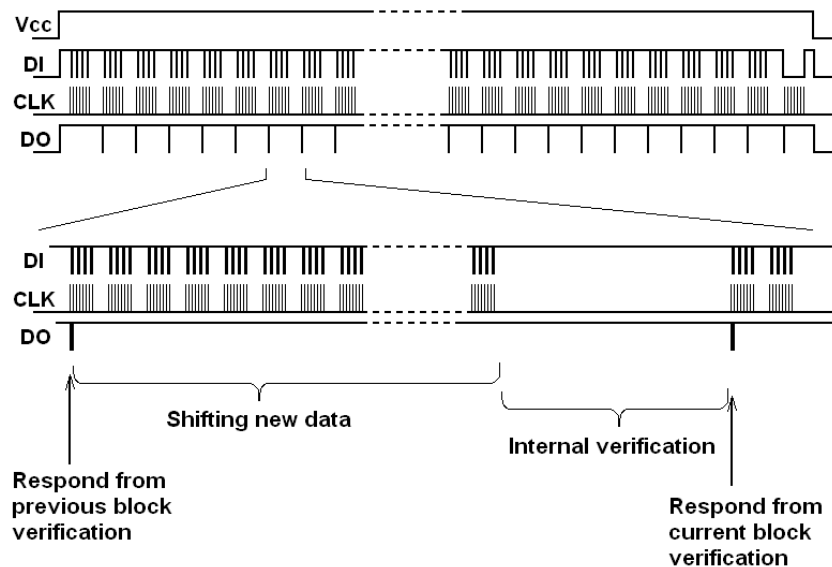
Background

- Flash memory structure
 - high voltages required for operation
 - narrow data bus
 - dedicated control logic



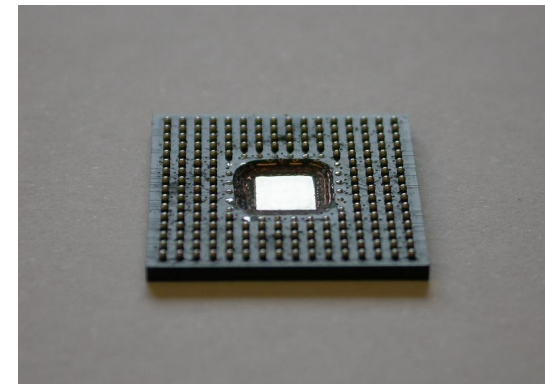
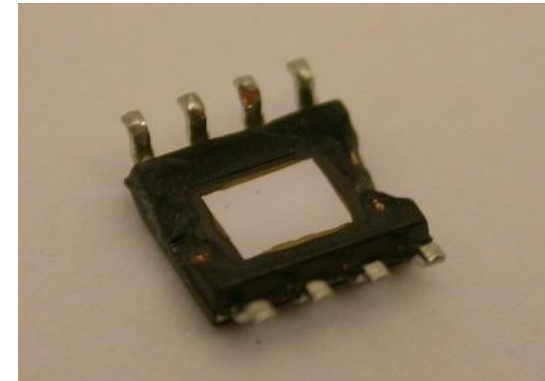
Background

- 'Bumping' is a certain type of physical attack on door locks
- Memory 'Bumping attacks' is a new class of fault injection attacks aimed at internal integrity check procedure in the chip
 - 'bumping' is aimed at blocks of data down to bus width
 - 'selective bumping' is aimed at individual bits within the bus



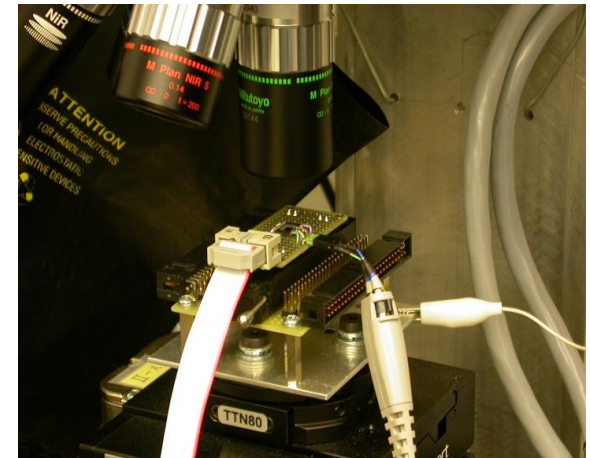
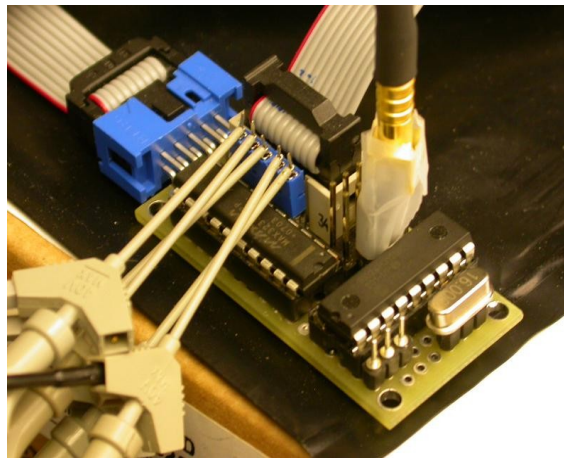
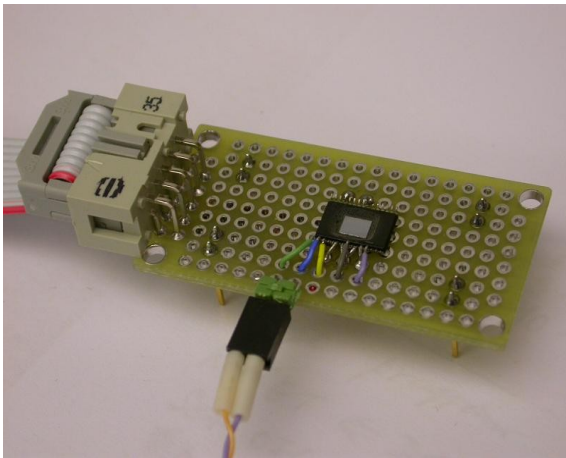
Experimental setup

- Sample preparation for modern chips (<math><0.5\mu\text{m}</math> and >2M)
 - only backside approach is effective
 - it is very simple and inexpensive
 - no chemicals are required



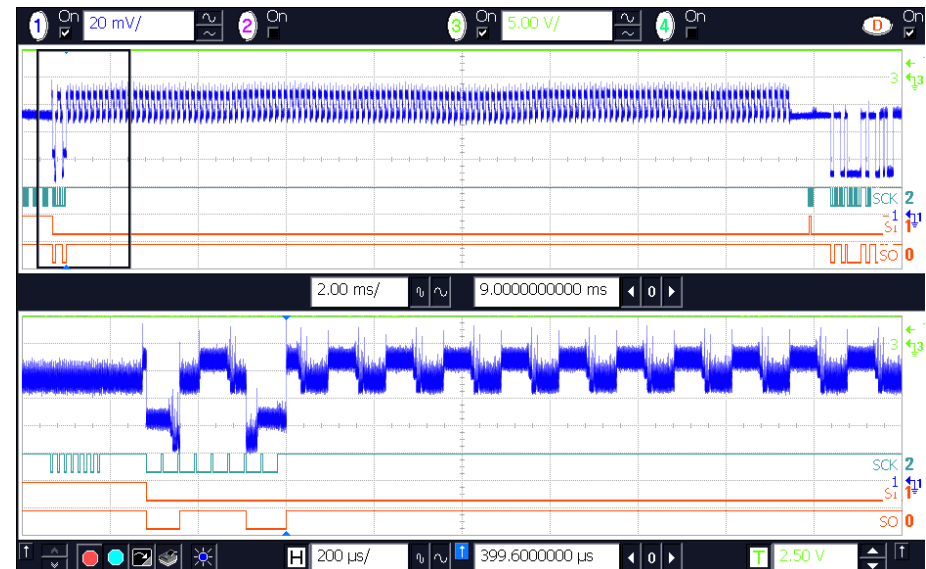
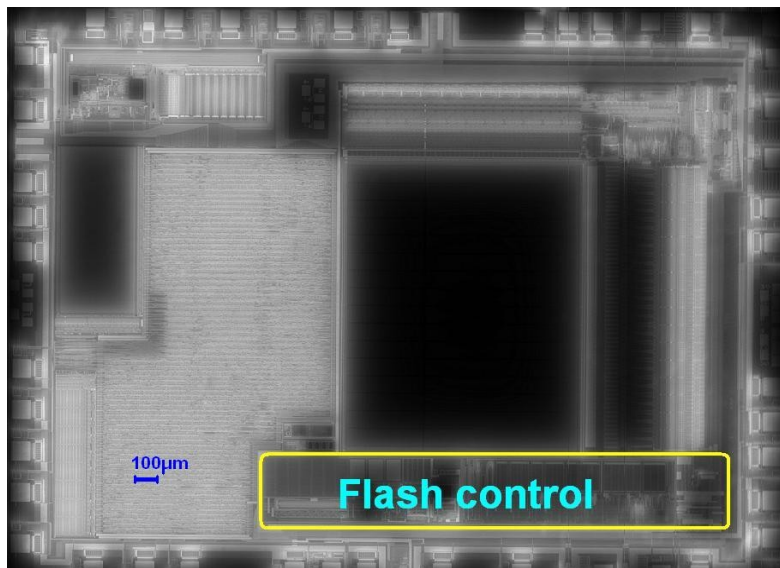
Experimental setup

- NEC 78K/0S μ PD78F9116 microcontroller with 16kB Flash
 - memory access via bootloader for Erase, Write, Verify, Blank Check
 - 0.35 μ m process with 3 metal layers
- Optical fault injection attack
 - 1065nm laser diode module with output power up to 100mW
 - NIR objective lens with 20 \times magnification



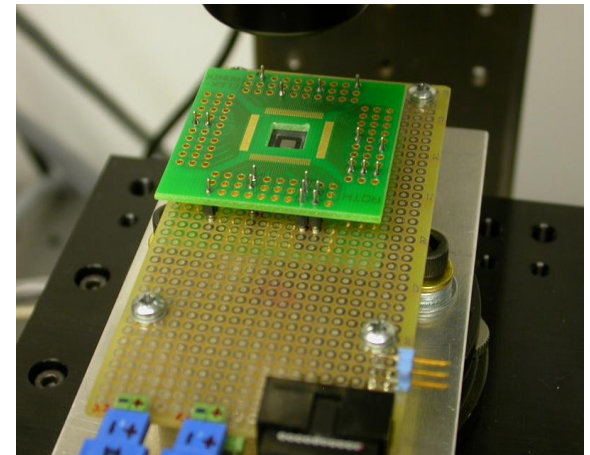
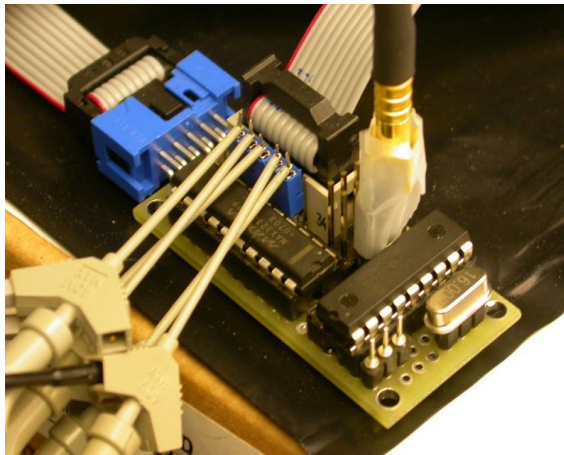
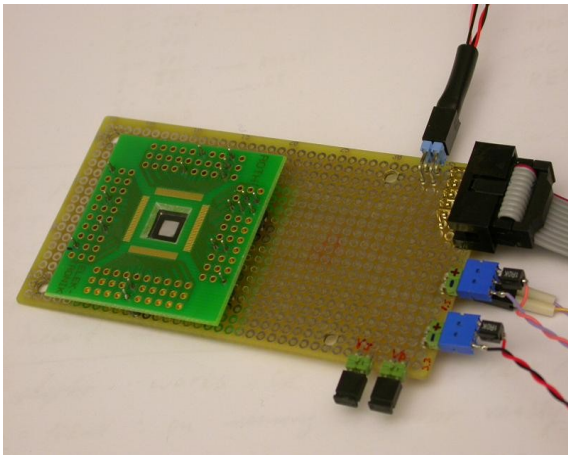
Results for bumping

- Locating Flash and active areas is easy (laser scanning)
- SPI interface for data transfer and SPA for timing analysis
- Memory matches all '0' when the laser is switched on
- Verification result is available only after all bytes are compared
- Data extraction time: 10 hours per block, or 2 months per chip
 2^7 attempts per byte, 128 bytes per block, 128 blocks, 2s per cycle



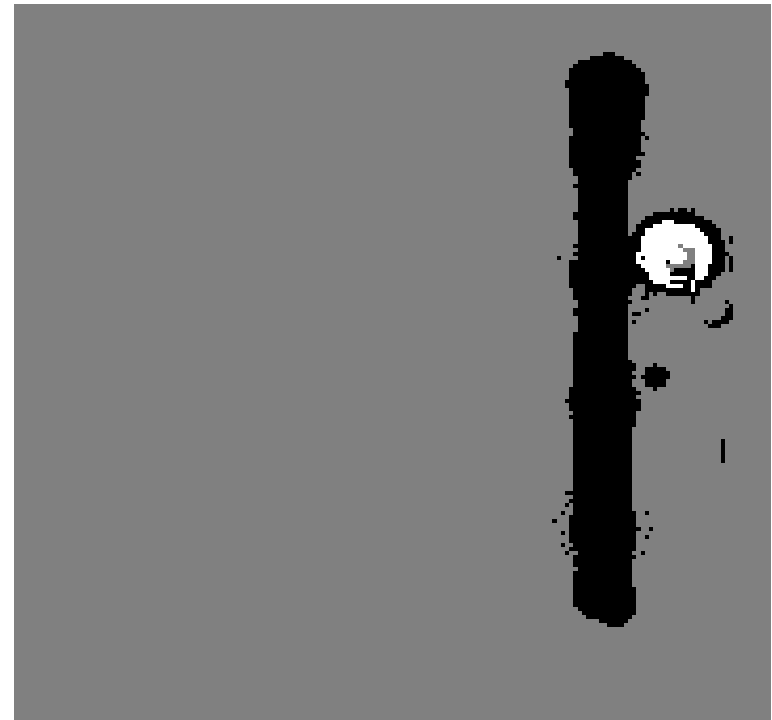
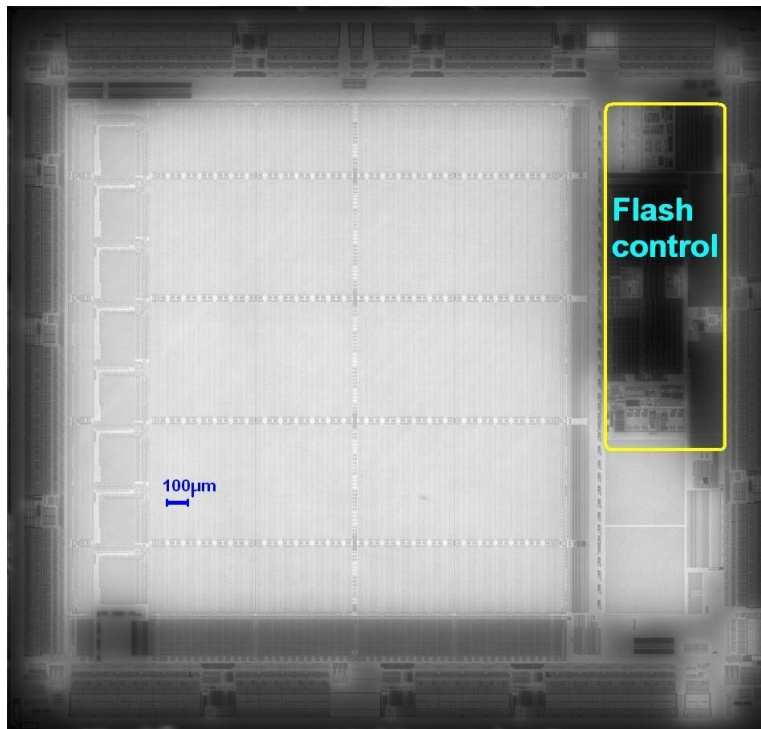
Experimental setup

- Actel ProASIC3 Flash-based A3P250 FPGA
 - memory access via JTAG for Erase, Program and Verify operations
 - 0.13 μ m process with 7 metal layers, limited information is available
 - “...offer one of the highest levels of design security in the industry”
 - “There is NO readback mechanism on PA3 devices”
 - soon after introduction of optical fault attacks I warned Actel about possible outcomes for Flash technology, but they showed no interest
- Same optical fault injection attack setup



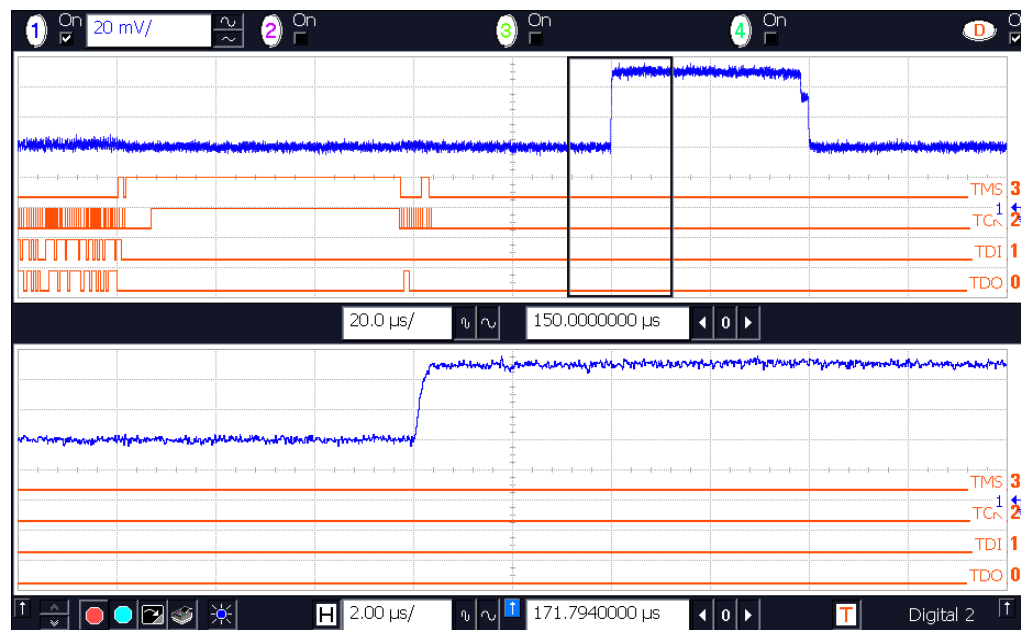
Results

- Locating Flash and active areas is easy (laser scanning)
- JTAG interface for data transfer
- Finding sensitive locations with exhaustive search (20 μ m)
black – data corrupted, white – matching all '1'



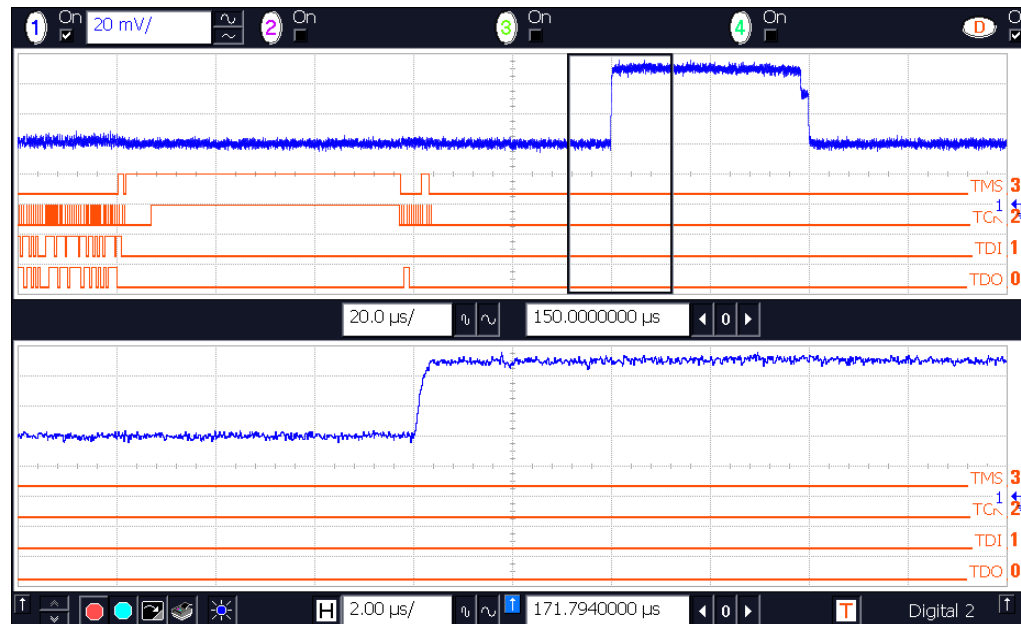
Results for bumping

- Using SPA for timing analysis: cannot detect data timing
- Verification result is available after each block of 832 bits
- 2300 blocks per array, 26 of 32-bit words per block
- Data extraction time: 18 years per block, 40000 years/chip
 2^{31} attempts per word, 26 words per block, 10ms per cycle



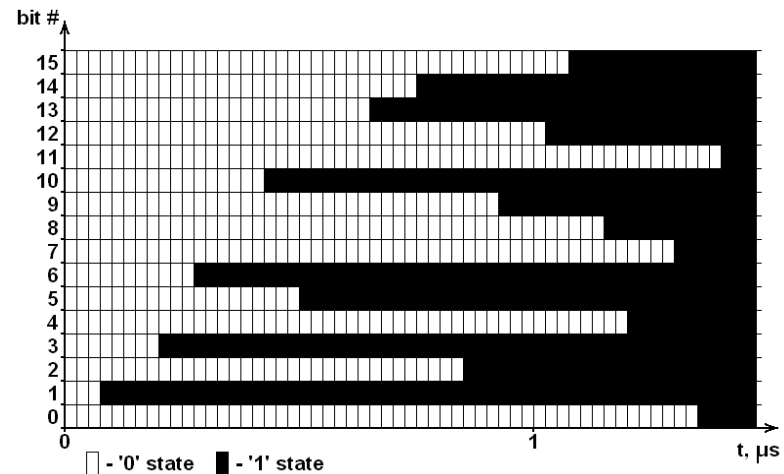
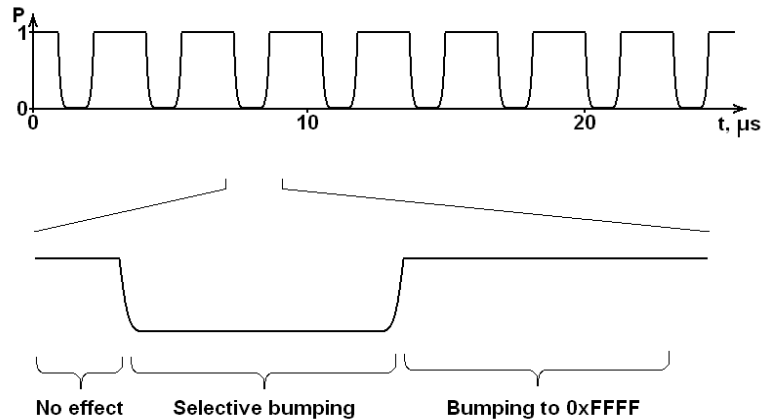
Results for selective bumping

- Using SPA results as a time reference
 - block verification $40\mu\text{s}$, 26 of 32-bit words per block, $1.5\mu\text{s}/\text{word}$
- Laser switching time was changed in 25ns steps
 - searching for single '0' bit, then two '0' and so on until passed
- Data extraction time: 30 minutes per block, 50 days/chip
 - 2^{13} attempts per word, 26 words per block, 10ms per cycle



Experimental setup

- Analysis of the selective bumping phenomenon using a secure microcontroller with AES authentication
 - not in production yet, supplied under NDA
 - hardware setup was supplied by industrial sponsor
 - chip was supplied pre-programmed with a test AES key
- Non-invasive power supply glitching attack was used
 - bumping: 2^{15} attempts per 16-bit word, 100ms cycle, 8 hours for AES key
 - selective bumping: 2^7 attempts per 16-bit word, 2 minutes for AES key



Attack time on 128-bit block

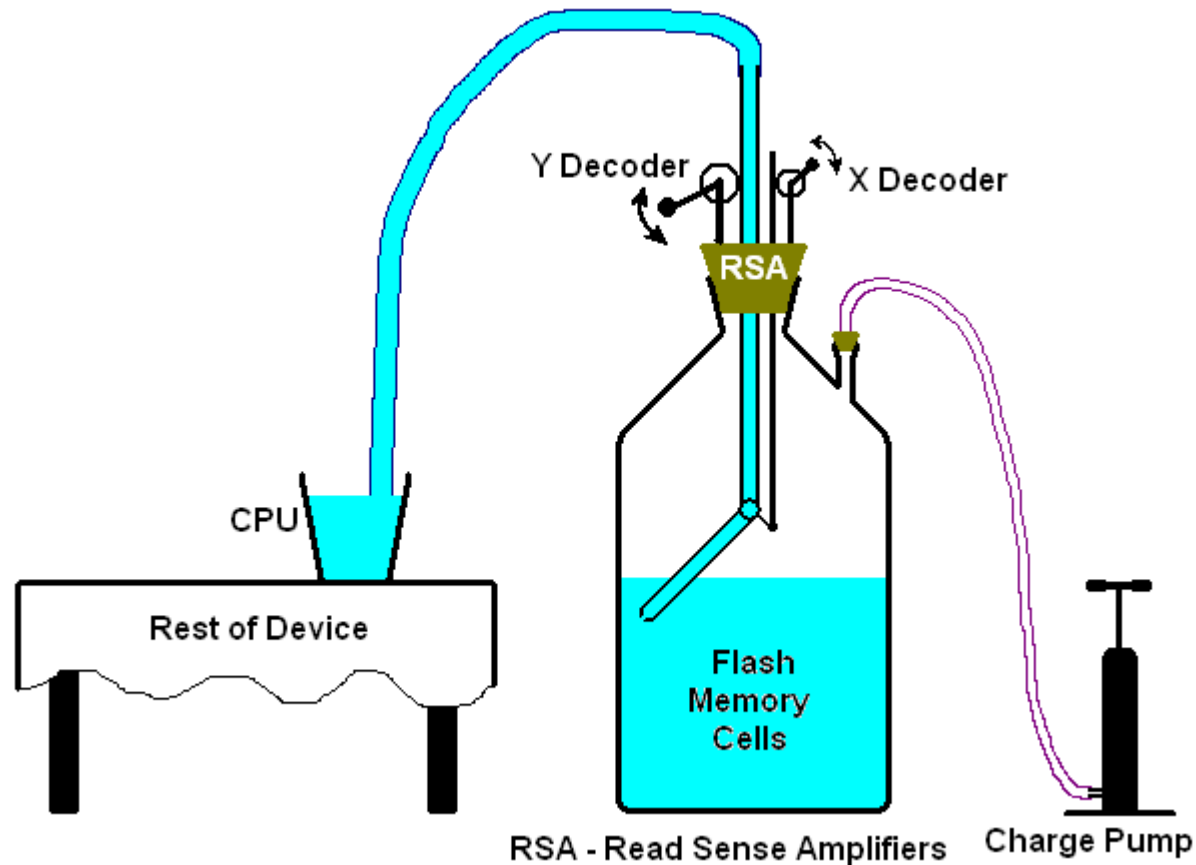
- Without any improvements: brute force search requires on average 2^{127} attempts
- Bumping: down to bus width
 - 8-bit bus: $2^7 \times 16 = 2^{11}$ attempts
 - 16-bit bus: $2^{15} \times 8 = 2^{18}$ attempts
 - 32-bit bus: $2^{31} \times 4 = 2^{33}$ attempts
- Selective bumping: down to single bit in limited steps
 - 8-bit bus: $(1+8+7+6+5+4+3+2+1) \times \frac{1}{2} \times 16 \approx 2^8$ attempts
 - 16-bit bus: $(1+16+15+\dots+2+1) \times \frac{1}{2} \times 8 \approx 2^9$ attempts
 - 32-bit bus: $(1+32+31+\dots+2+1) \times \frac{1}{2} \times 4 \approx 2^{10}$ attempts
- In a real attack the complexity could be higher due to the granularity of the delay time and timing jitter
 - 32-bit bus: $(1+32+31+\dots+2+1) \times \frac{1}{2} \times 4 \times 8 \times 4 \approx 2^{15}$ attempts

Limitations and countermeasures

- Slow process
 - depends on the implementation of data verification or authentication
- Precision timing is not necessary
 - slowly increase the delay until the effect is observed
- Selective bumping attacks have partial repeatability
 - between words in the row and between memory rows
- Fault attacks can be carried out with glitching or optically
 - optical attacks on modern chips require backside approach
- Precise positioning for optical attacks is not necessary
- Encryption and redundancy check make analysis harder
- Asynchronous circuits could make the attack more problematic as bumping requires predictable timing
- Understanding the core of a problem is vital

Why Flash memory fails?

- Flash memory in a nutshell – for better understanding
 - can you see the bottleneck(s)?



Improvements and Future work

- Security with no readback is not the only one in ProASIC3
 - passkey access protection, AES encryption, security fuses
- Moving away from semi-invasive attacks toward using non-invasive attacks like in the last example with AES key extraction from the secure microcontroller
 - easier to setup for deep-submicron chips
 - faster to get the result
 - pose larger threat to the hardware security
- Using data remanence effect for bumping through threshold voltage adjustment
 - S. Skorobogatov: Data Remanence in Flash Memory Devices, CHES-2005, LNCS 3659, pp.339–353
- Testing other chips for strength against firmware and secret key extraction

Conclusions

- Bumping attacks are dangerous and can compromise the security in chips – evaluation and protection is necessary
- Backside approach helps in modern chips, it is simple to do and does not require expensive optics and precise positioning
- Bumping attacks can be used for partial reverse engineering to understand internal data paths and chip structure
- If you do not want to get screwed talk to experts in academia; there are solutions for increasing the security of chips

